

Notice of References Cited	Application/Control No. 09/863,861		Applicant(s)/Patent Under Reexamination VINJE, VETLE	
	Examiner Toan M Le		Art Unit 2862	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6094621	07-2000	Hanitzsch et al.	702/16
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
X	U	"Multiple Weights in Diffraction Stack Migration", Tygel et al., Geophysics, Vol. 59, No. 12, pages 1820-1830, 12/1993
X	V	"Angle-Dependent Reflectivity by Means of Prestack Migration", de Bruin et al., Geophysics, Vol. 5, No. 9, pages 1223-1234, 9/1990
	W	"3-D True-Amplitude Finite-Offset Migration", Schleicher et al., Geophysics, Vol. 58, No. 8, August 1993, Pages 1112-1126
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.